

Deep Lithography for Microfabrication

Part 2: UV Deep Lithography (UVDL)

Luiz O. S. Ferreira

Mechanical Engineering Faculty

Campinas State University –
UNICAMP

Campinas – SP - BRAZIL

lotavio@fem.unicamp.br

Acknowledgments

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- LNLS

- People

- LNLS staff: Grazielle Natal, Angelo Gobbi

Presentation Outline

- ❑ Introduction
- ❑ Positive-tone Resists for UDVL
- ❑ Dry films on UDVL
- ❑ Gray tone lithography
- ❑ The SU8 photoresist
- ❑ Inclined lithography
- ❑ Final remarks

Introduction

❑ Before 1996

- Thick resists were used primarily as electroplating mold material.
 - UV lithography on PMMA: < 5 μ m thick
 - Positive tone resists: < 50 μ m thick
 - Negative tone resists: < 150 μ m thick (polyimide)

❑ 1996 SU-8 is released

❑ After 1996

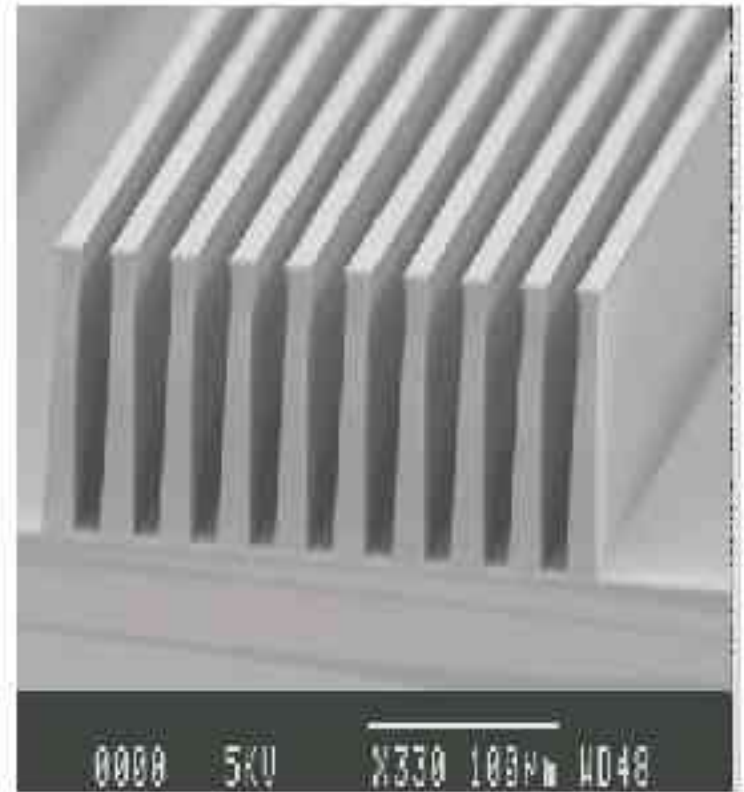
- New applications to UV deep lithography
- UV-LIGA; HARMST

Positive-tone Resists for DUVL

- ❑ Thickness limited by transparency
 - Thickness < 150 μm
 - Aspect-ratio (7 – 15)
 - Easy removal
 - Good as mold for electroplating
 - Bad as structural material

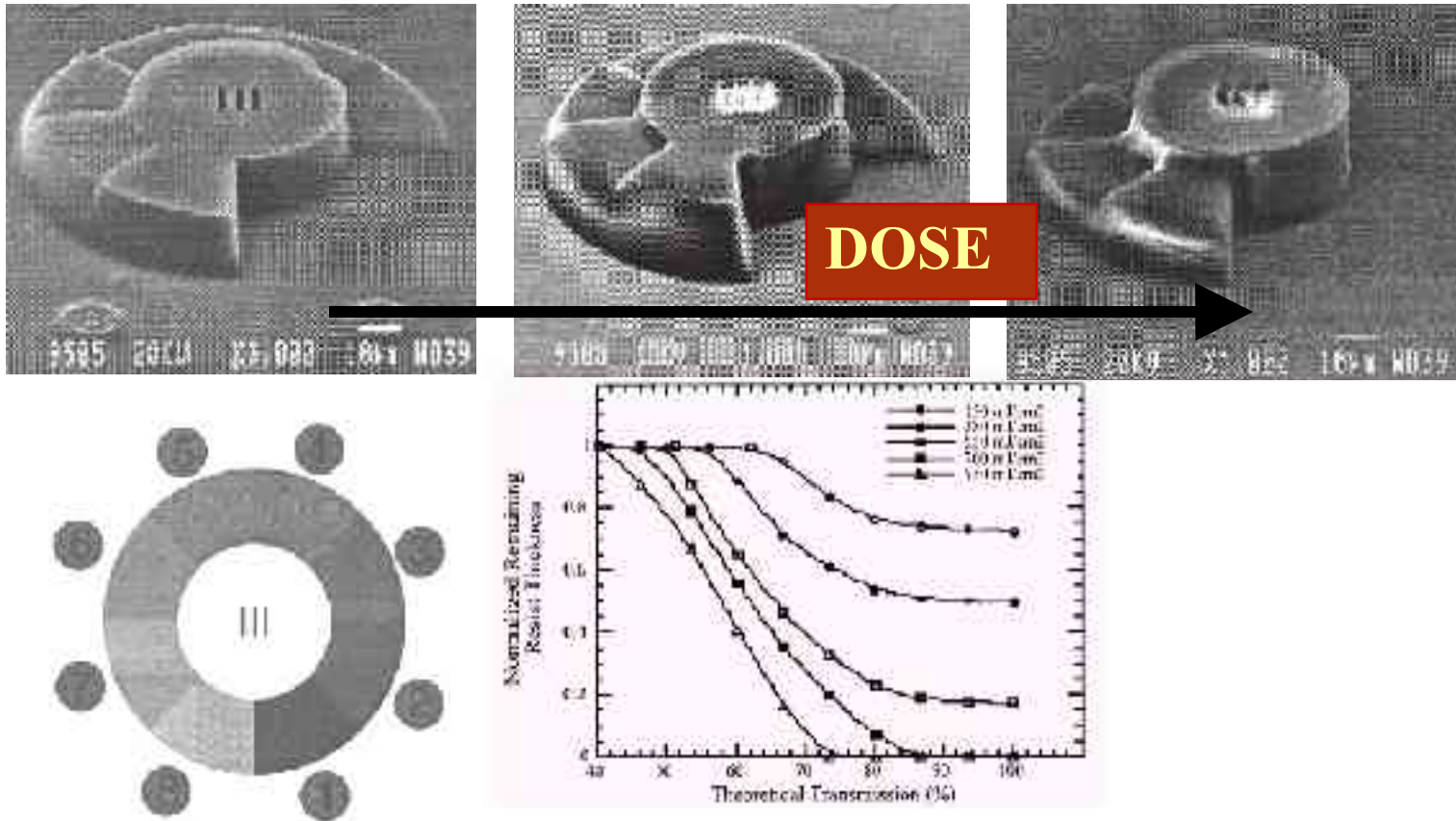
Positive-tone Resists for DUVL

- ❑ 100 μm thick film.
- ❑ Spinning tips:
 - Use ramped speed profile
- ❑ Confined spinner chamber helps on thicker films



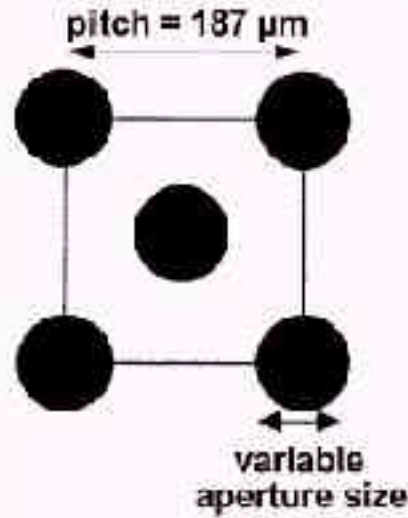
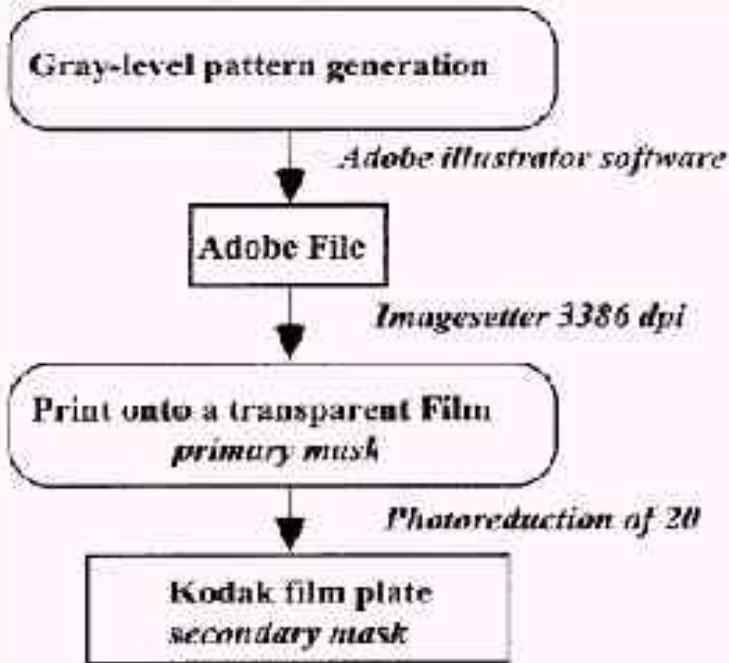
Picture from: V Conedera, B Le Goff and N Frabre,
“Potentialities of a new positive photoresist for the realization
of thick moulds”, *J. Micromech. Microeng.*, **9** (1999) 173-175.

Gray-tone Lithography - 1



From: S. Nicolas, E Dufour-Gergam, A Bosseboeuf, T Bourouina, J-P Gilles and J-P Grandchamp, "Fabrication of a gray-tone mask and pattern transfer in thick photoresists," *J. Micromech. Microeng.*, **8** (1998) 95-98.

Gray-tone Lithography - 2



Gray-tone binary mask.
PWM of the light intensity
Scale = 200.
Constant pitch.
256 levels of gray.

An additional reduction of 10X was used to transfer the 3D pattern from the secondary mask into photoresist.

From: S. Nicolas, E Dufour-Gergam, A Bosseboeuf, T Bourouina, J-P Gilles and J-P Grandchamp, "Fabrication of a gray-tone mask and pattern transfer in thick photoresists", *J. Micromech. Microeng.*, **8** (1998) 95-98.

Negative-tone Resists for DUVL

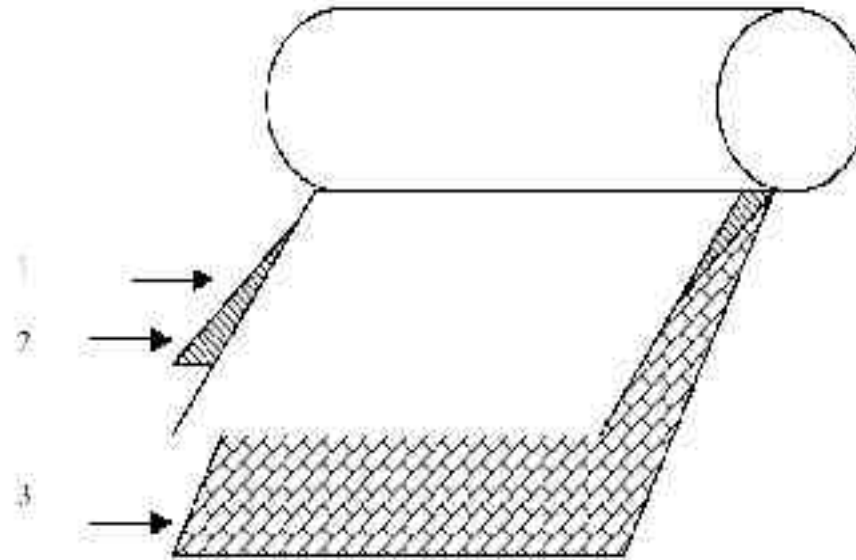
- ❑ Exceptional transparency
 - Thickness 1000 μm
 - Aspect-ratio: 5-25
 - Good as mold for electroplating
 - Some resists are good as structural material
 - Dry film and liquid resists.

Dry Films on DUVL

- ❑ From PCB industry.
 - 20 μm , 50 μm and other thickness.
 - > 200 μm on multilayer.
 - Laminated on the substrate.
 - Good for electroplating.
 - Easy stripping.

From: E. Kukhareuka, M M Farooqui, L Grigore, M Kraft and Hollingshead,
“Electroplating moulds using dry film thick negative photoresist”*J.*
Micromech. Microeng., **13** (2003) S67-S74.

Dry Films on DUVL - Structure



Three-layer structure of dry film photoresist.
1: polyethylene separation sheet; 2: photoresist and 3: polyester support.

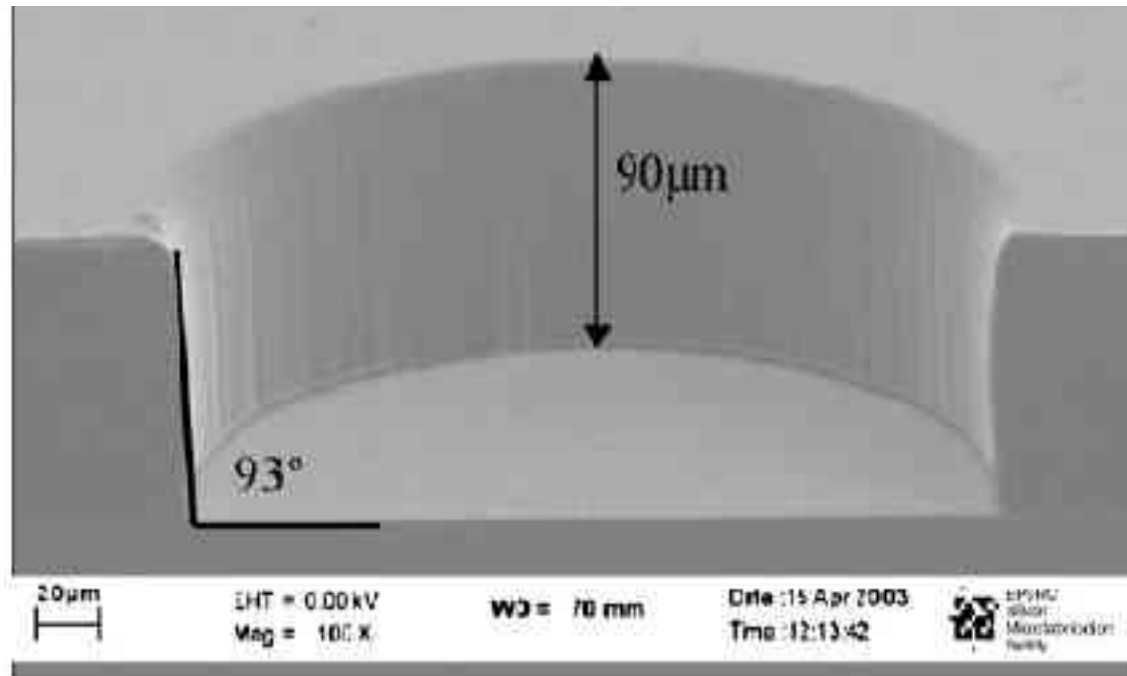
From: E. Kukharenka, M M Farooqui, L Grigore, M Kraft and Hollingshead, **“Electroplating moulds using dry film thick negative photoresist”**, *J. Micromech. Microeng.*, **13** (2003) S67-S74.

Dry Films on DUVL - Processing

- ❑ Peeling of the polyethylene film.
- ❑ Lamination to the substrate.
- ❑ Conformation by heating under pressure.
- ❑ UV exposure.
- ❑ Peeling of the polyester film.
- ❑ Development.

From: E. Kukharenka, M M Farooqui, L Grigore, M Kraft and Hollingshead, “**Electroplating moulds using dry film thick negative photoresist**”, *J. Micromech. Microeng.*, **13** (2003) S67-S74.

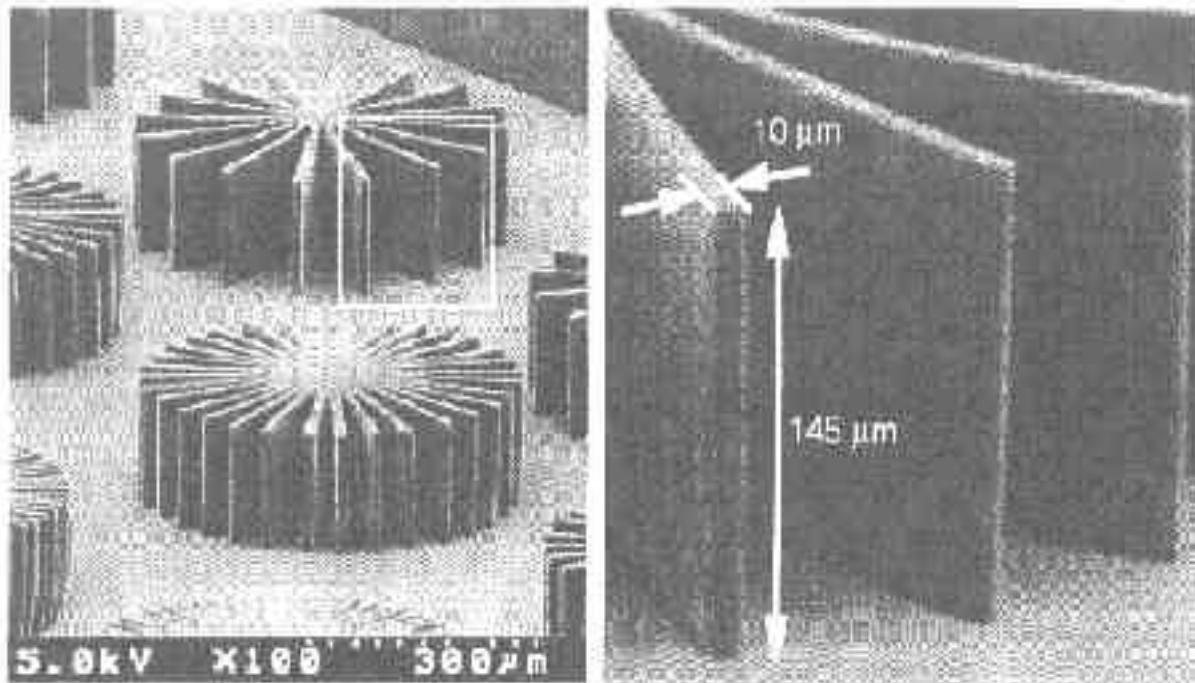
Dry Films on DUVL - Sample



SEM image of 90 μm thick mould in Ordyl P-50100.

From: E. Kukharenka, M M Farooqui, L Grigore, M Kraft and Hollingshead, **“Electroplating moulds using dry film thick negative photoresist”**, *J. Micromech. Microeng.*, **13** (2003) S67-S74.

The SU8 Photoresist



- ❑ Negative-tone, high aspect ratio, near UV epoxy based photoresist.
- ❑ Good mechanical, electrical, optical and chemical properties.
- ❑ UV-LIGA

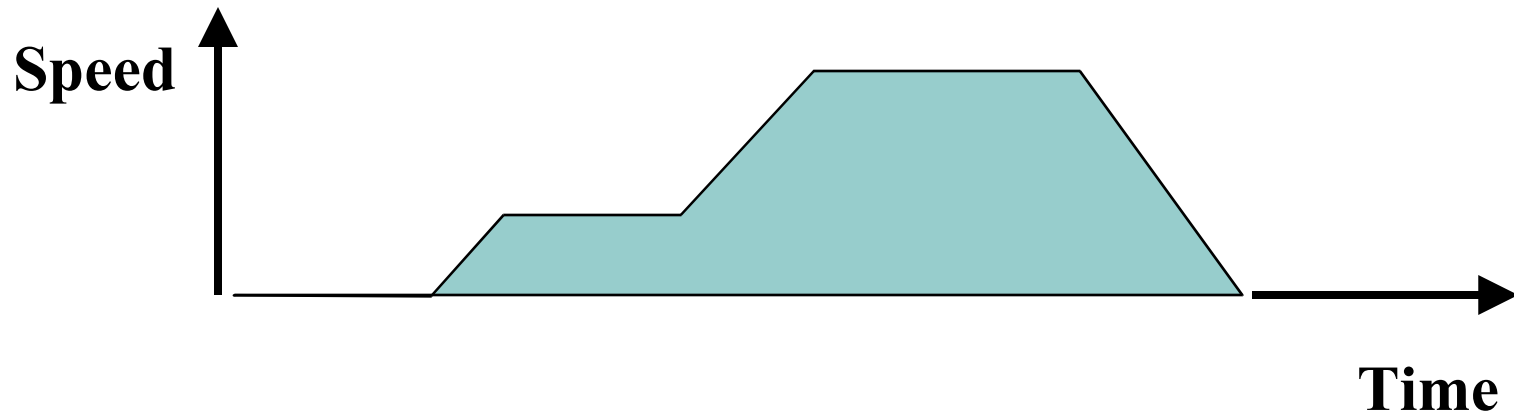
From: H Lorenz, M Despont, N Fhrni, N LaBianca, P Renaud and P Vettiger, “SU-8: a low-cost negative resist for MEMS”, *J Micromech. Microeng.* 7 (1997) 121-124

SU8 - General

- ❑ It was developed by IBM for e-beam lithography.
- ❑ Highly transparent to near UV
- ❑ EPON[®] Resin SU-8, from Shell Chemical, dissolved in an organic solvent (GBL or cyclopentanone) plus a photoinitiator.
- ❑ Chemical amplification by a post-bake.
- ❑ Stripping with hot NMP (1-methyl-2-pyrrolidone), plasma or laser ablation.
- ❑ Hard baked (30 min @ 200 °C): withstands nitric acid, pH 13 NaOH @ 90 °C, etc.

From: H Lorenz, M Despont, N Fhrni, N LaBianca, P Renaud and P Vettiger, “**SU-8: a low-cost negative resist for MEMS**”, *J Micromech. Microeng.* 7 (1997) 121-124

SU-8 Processing - Spinning



- ❑ Low speed for spreading the resist on the substrate.
- ❑ High speed for thinning the resist film.
- ❑ Use ramped speed changes (100-200 rpm/s).

SU-8 Processing - Soft-bake

- ❑ Temperature = 95°C.
- ❑ Tg = 55°C for unexposed film.
- ❑ Hotplate is preferable to oven.
- ❑ Hotplate **must be** levelled.

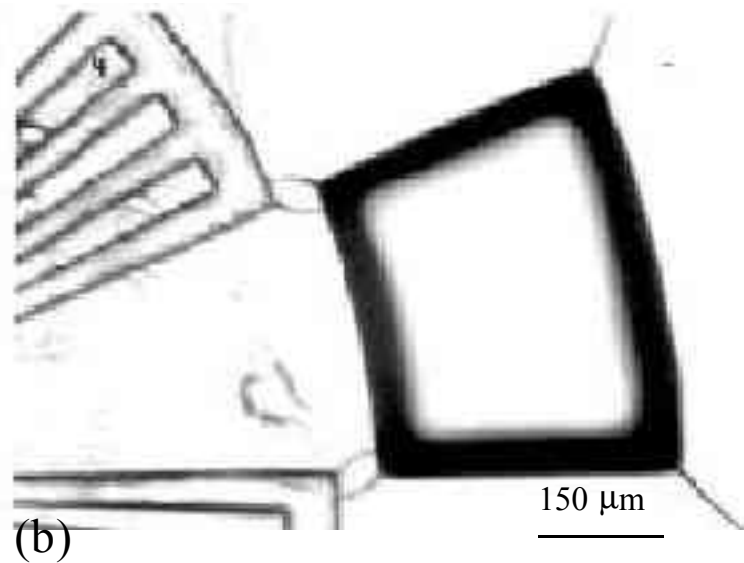
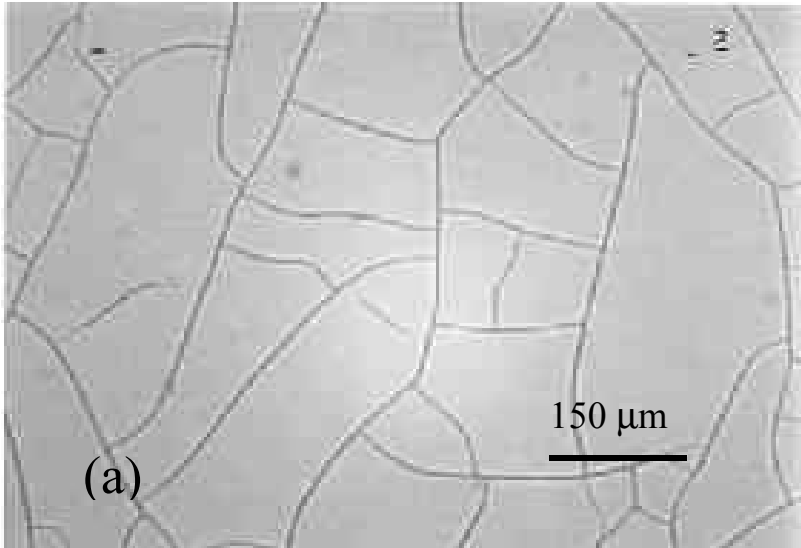
SU-8 Processing - Exposure

- ❑ For thick films:
 - Fraction your dose on short exposures and one minute intervals to avoid crust formation.
- ❑ 130 μm thick film: 165 mJ/cm^2 .

SU-8 Processing - Post-bake

- ❑ More crosslinked when heated.
- ❑ Crosslinked film: $T_g > 200^\circ\text{C}$
- ❑ Cooling cycle:
thermal expansion mismatch produces stress.
- ❑ Thermal expansion:
 - **SU-8:** **21-52 ppm/K**
 - **Si:** **2.36 ppm/K**

SU-8 Processing – Stress - 1

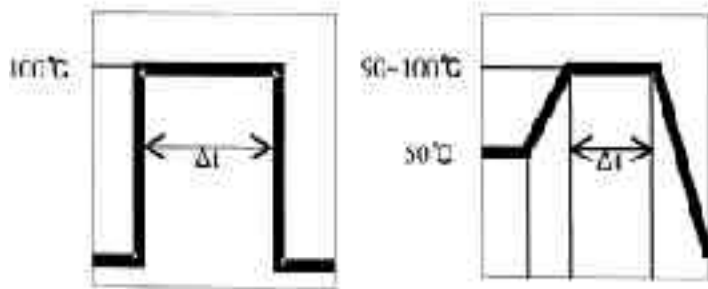


SU-8 Processing – Stress - 2

Expose Dose PEB (Δt)	120mJ/cm ²	180mJ/cm ²	240mJ/cm ²	300mJ/cm ²
5min				
10min				
15min				
25min				

From: Hyun-Kee Chang and Yong-Kweon Kim, “UV-LIGA process for high aspect ratio structure using stress barrier and C-shaped etch hole”, *Sensors and Actuators*. **84** (2000) 342-350

SU-8 Processing – Stress - 2



Exposure Dose PER (Δt)	120mJ/cm ²	180mJ/cm ²	240mJ/cm ²	300mJ/cm ²
1min				
3min				
5min				
10min				

From: Hyun-Kee Chang and Yong-Kweon Kim, “UV-LIGA process for high aspect ratio structure using stress barrier and C-shaped etch hole”, *Sensors and Actuators*. **84** (2000) 342-350

SU-8 Processing - Development

- ❑ (for a 130 μm thick film)
 - A) 5 min in pure developer PGMEA (propylene glycol methyl ether acetate)
 - B) Rinse with IPA
 - C) Repeat steps A and B until no white stains remain.
- ❑ **WARNING:** do not rinse with water.

SU-8 Processing - Stripping

- ❑ Lift off : easy.
- ❑ Piranha: ($\text{H}_2\text{SO}_4:\text{H}_2\text{O}_2$)
- ❑ Plasma etch
- ❑ Laser ablation

SU-8 Processing - Hardbake

- ❑ 30 min @ 200°C
- ❑ After hardbake it withstands chemicals like nitric acid, KOH, NaOH, acetone, etc.

SU8 Properties - Mechanical

Modulus of elasticity : E	4.02 GPa
-	4.95 +/- 0.42 GPa
-	4.4 GPa
Bi-axial modulus of elasticity : $E/(1 - \nu)$	5.18 +/- 0.89 GPa
Poisson ratio	0.22 postbaked at 95C, SM blend
Film stress	19 - 16 Mpa
Max stress	34 Mpa
Max sheer	0.009
Plastic domain limit	'no' plastic domain observed
Friction coefficient : μ	0.19

From: <http://aveclafaux.freesevers.com/SU-8.html>

SU8 as structural material

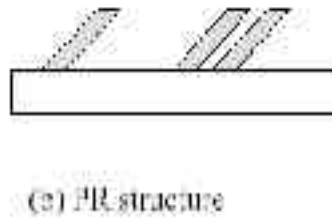
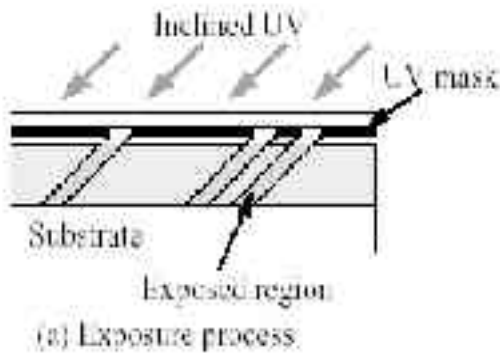
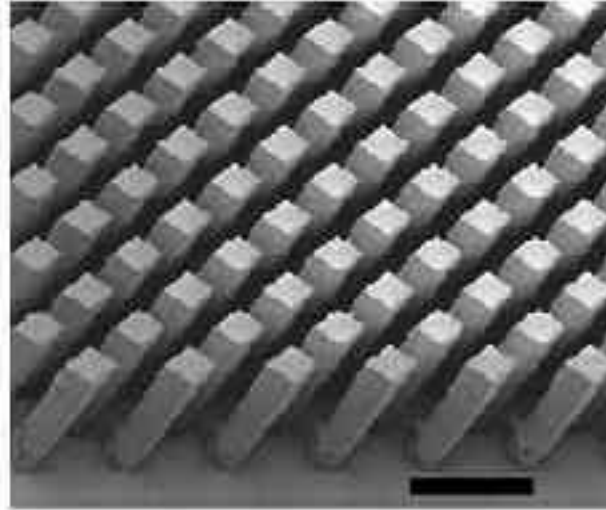
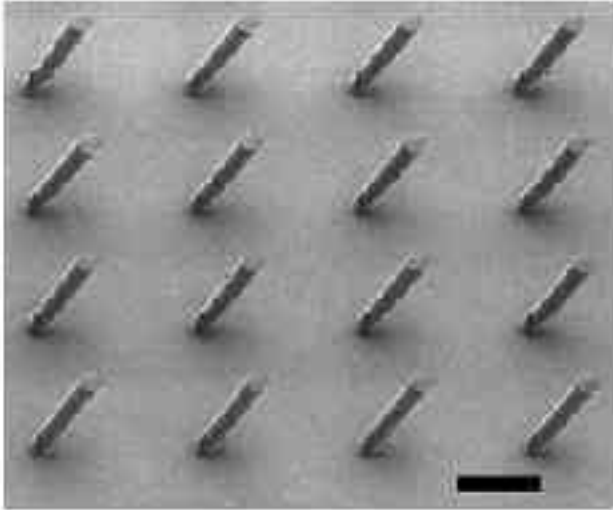


SU8 Properties - Other

- ❑ Aspect ratio: 1:20 and 1:25 typical
- ❑ May be gray-tone lithographed.
- ❑ May be MeV proton lithographed.
- ❑ Adhesion is good but depend on the material.
- ❑ Have good biocompatibility.

From: <http://aveclafaux.freesevers.com/SU-8.html>

SU-8 Inclined Lithography - 1



TRACE = 100 μm

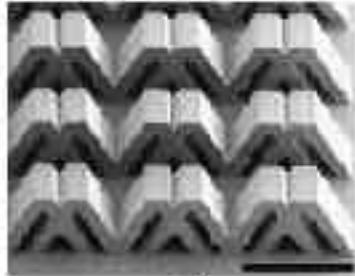
From: Manhee Han, Woonseob Lee, Sung-Keun Lee, Seung S Lee, "3D microfabrication with inclined/rotated UV lithography", *Sensors and Actuators.A* 111 (2004) 14-20

SU-8 Inclined Lithography - 2

Several inclined exposures



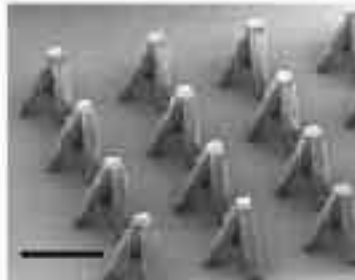
(a)



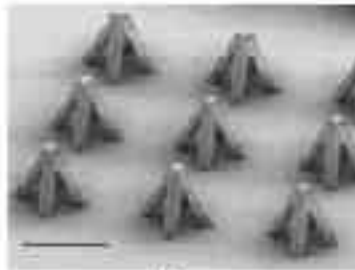
(b)



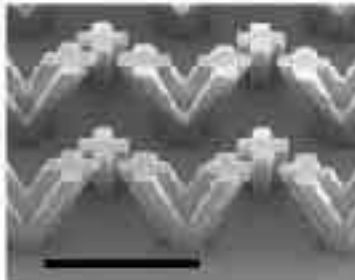
(c)



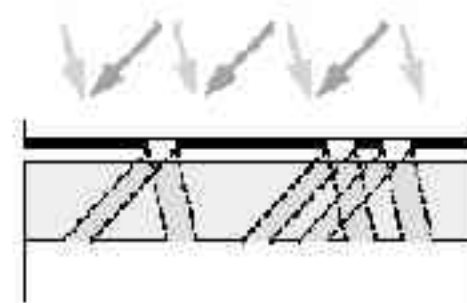
(d)



(e)



(f)



(a) Exposure process

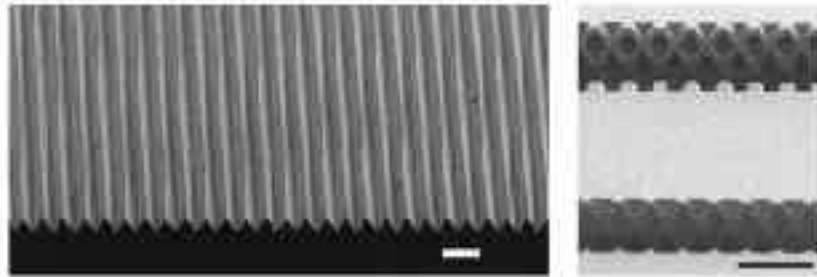


(b) PR structure

TRACE = 200 μm

From: Manhee Han, Woonseob Lee, Sung-Keun Lee, Seung S Lee, "3D microfabrication with inclined/rotated UV lithography", *Sensors and Actuators.A* 111 (2004) 14-20

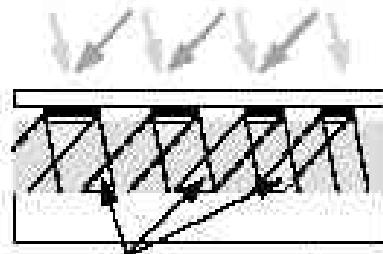
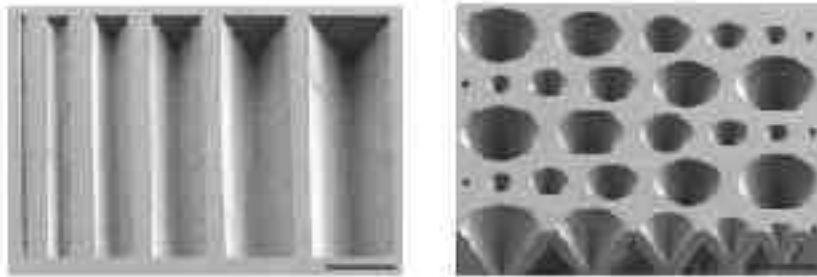
SU-8 Inclined Lithography - 3



(a)

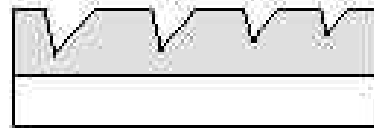
(b)

Double inclined exposure.



Enclosed unexposed PR

(a) Exposure process

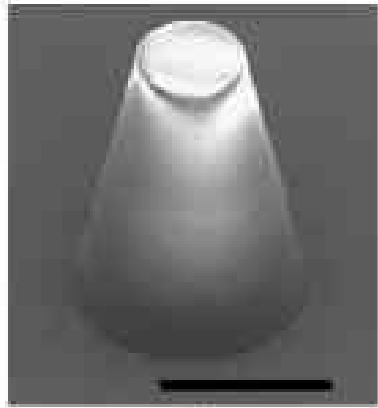


(b) PR structure

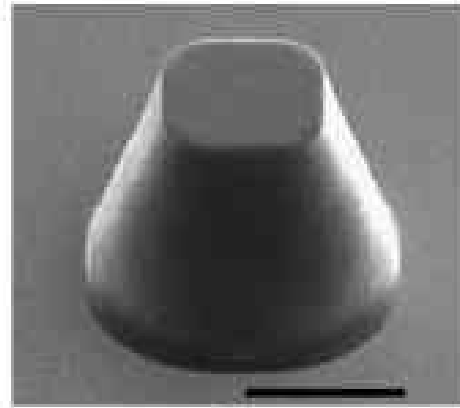
TRACE = 100 μm

From: Manhee Han, Woonseob Lee, Sung-Keun Lee, Seung S Lee, "3D microfabrication with inclined/rotated UV lithography", *Sensors and Actuators.A* 111 (2004) 14-20

SU-8 Inclined Lithography - 4

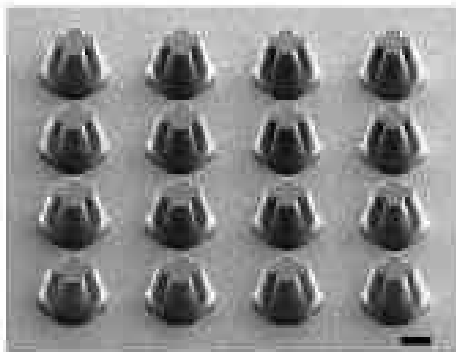


(a)

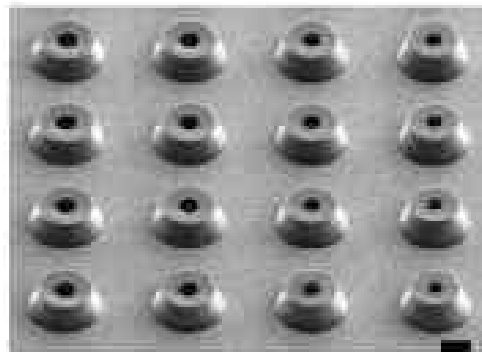


(b)

Inclined and rotated exposure.



(c)

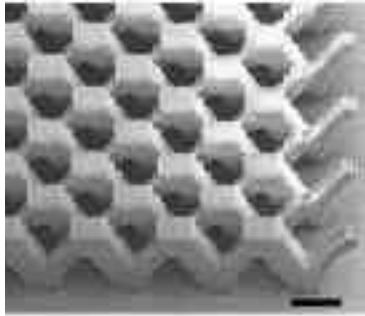


(d)

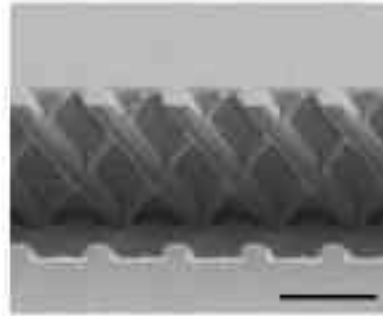
TRACE = 50 μm

From: Manhee Han, Woonseob Lee, Sung-Keun Lee, Seung S Lee, "3D microfabrication with inclined/rotated UV lithography", *Sensors and Actuators.A* 111 (2004) 14-20

SU-8 Inclined Lithography - 5



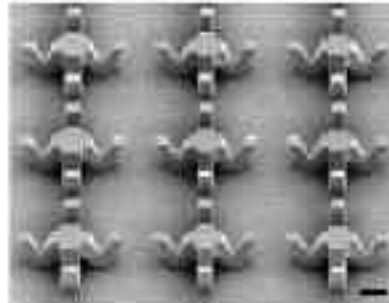
(a)



(b)



(c)



(d)



**Reflected UV
exposure.**

TRACE = 50 μm

From: Manhee Han, Woonseob Lee, Sung-Keun Lee, Seung S Lee, "3D microfabrication with inclined/rotated UV lithography", *Sensors and Actuators.A* 111 (2004) 14-20

Final Remarks

- ❑ Deep lithography is on its beginning.
- ❑ Many resists from industry branches other than microelectronics have potential for use on deep lithography.
- ❑ Gray tone have good evolution potential. It is interesting mainly to fluidics and photonics.
- ❑ MeV proton looks to be a strong competitor to DXRL.
- ❑ Inclined/rotated lithography may be a real enhancement to actual techniques.

The End

- ❑ THANKS FOR ATTENTION.
- ❑ QUESTIONS?